Notice of References Cited Application/Control No. 10/017,490 Examiner Chau N Nguyen Applicant(s)/Patent Under Reexamination SEGALL ET AL. Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,330,811	07-1994	Buchalter, Mark R.	428/40.9
	В	US-4,501,929 /	02-1985	Escallier et al.	174/117F
	С	US-2002/0104676	08-2002	Treutlein et al.	174/117.00F
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP6-176629 /	06-1994	Japan	Yamagishi	
	0					
	Р					
	Q			·	·	
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	٧							
	w							
	x							

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.